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		Application Number	10/750,838-Conf. #2502		
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Filing Date	January 5, 2004		
		First Named Inventor	Shuichi Takeuchi		
		Art Unit	NTA 2881		
		Examiner Name	Not Yet Assigned Fernandez		
Sheet	1	of	1	Attorney Docket Number	H6808.0032/P032

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
KE	AA**	6,538,249	03-25-2003	Takane et al.	
KE	AB**	6,353,222	03-05-2002	Noam Dotan	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
KE	BA	JP 2001-84944	03-30-2001			
	BB	JP 2001-118537	04-27-2001			
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	BD	JP 2002-75263	03-15-2002			
KE	BE	JP 2002-184336	06-28-2002			

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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
KE	CA	A. Muto et al., "Attempts to Improve SEM Image Quality by Special Imaging Feature." Proceedings of the Fifty-Eighth Annual Meeting of the Japanese Society of Electron Microscopy, May 14-16, 2002, pp.246. English Translation.	
	CB	M. Sato et al., "Depth of Field at High Magnifications of Scanning Electron Microscopes." J. Vac. Sci. Technol. B 18(6), Nov/Dec. 2000, pp.3047-3051.	
	CC	T. Kogashiwa et al., "Automatic Adjustment Function of Optical Axis, and automatic Expansion Function of Focal Depth." SCAN TECH 2002, Preliminary Report, September 2002, pp. 2-6. English Translation.	
KE	CD	Norio Baba, "Three-dimensional Automatic Measurement by the Stereoscopic Observation Method." SCAN TECH 2000, Preliminary Report, September 2000, pp. 28-32. English Translation.	

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